

**Amendments to the Specification:**

Please delete the Abstract and replace it with the following paragraph:

--An apparatus permits built-in self-test ("BIST") of an IC that includes a memory element having more than one impermissible operation. A code generator accepts a clock signal and generates a test code in response to it. A decoder accepts the test code and generates at least two output lines to disable the impermissible operations during the test. When the decoder is in a decode disabled condition, the output lines reflect a value that permit all possible memory operations.--